

<b>Notice of References Cited</b>	Application/Control No. 10/578,026		Applicant(s)/Patent Under Reexamination VAN BEEK ET AL.	
	Examiner KAREN M. KUSUMAKAR		Art Unit 2829	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0059720	03-2003	Hwang et al.	430/311
*	B	US-2001/0051302	12-2001	DOVE et al.	430/5
*	C	US-5,949,071	09-1999	Ruffner et al.	250/338.3
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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